Jeffrey R. Swe	earingen 2445	Page 1 of 1	
Examiner	Art Unit		
Notice of References Cited		Reexamination HAYASHI ET AL.	
Application/Co	'''	Applicant(s)/Patent Under	

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,560,651	05-2003	Katz et al.	709/229
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FOREIGN PATENT DOCUMENTS

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